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L15	select$3 with finishing	3681	L15
L14	preflight same stapl$4	0	L14
L13	L8 and job ticket	9	L13
L12	L10 and finishing	45	L12
L11	L10 and l4	5	L11
L10	collat$4 and registration and bind$3 and cut$4 and hole	101	L10
L9	L6 and l3	354	L9
L8	L6 and l4	756	L8
L7	L6 and l5	245	L7
L6	(alternat$4 or substitu$5)	2268945	L6
L5	finishing and user (profile or preference)	312	L5
L4	finishing same (profile or preference)	2370	L4
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Bradley, E.; Banerji, K.;
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[Abstract]   [PDF Full-Text (2472 KB)] **IEEE CNF**

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Curran, T.; Benjamin, D.M.; Austin, S.;
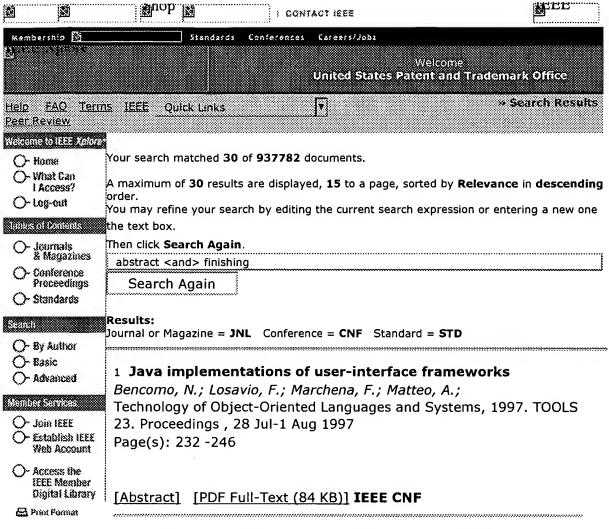Simulation Conference Proceedings, 1998. Winter , Volume: 2 , 13-16
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